

## Technical Data Sheet

### TSS 400 F

#### XRF average chemical analysis :

SiO <sub>2</sub>	99.45	%
Al <sub>2</sub> O <sub>3</sub>	0.17	%
Fe <sub>2</sub> O <sub>3</sub>	Media 380 (max 430)	ppm
TiO <sub>2</sub>	0.01	%
CaO	0.01	%
MgO	0.01	%
K <sub>2</sub> O	0.03	%
Na <sub>2</sub> O	0.01	%
P.F (1100°C)	0.03	%

#### Average grain size distribution

Size	Weight (%)
>1mm	0%
1mm - 630μ	0.1%
630μ -500μ	1.3%
500μ -400μ	4.3%
400μ -315μ	28.5%
315μ-200μ	27.4%
200μ-100μ	36.2%
100μ -75μ	1.7%
<75μ	0,2%

#### Other characteristics

Moisture (%)	< 4,5%
--------------	--------

SONEVAM  
Mr. Carlo Cerchi  
Technique

